Energy minimization in thin-film micromagnetics

Samuel Ferraz-Leite* (TU Wien), Jens Markus Melenk (TU Wien), Dirk Praetorius (TU Wien)

The steady state of a magnetization **M** of a ferromagnetic sample Ω was first described by Landau and Lifschitz as the solution of a certain minimization problem, which is nowadays accepted as the relevant model to describe micromagnetic phenomena. However, micromagnetics is one prototype of a non-convex and non-local multiscale problem and, from a numerical point of view, thus hardly accessible.

In [3], a reduced model for thin-film micromagnetics has been introduced which is consistent with the prior works [1] and [5]. Let $\omega \subseteq \mathbb{R}^2$ denote a bounded Lipschitz domain with diameter $\ell = 1$. This domain represents our ferromagnetic sample $\Omega = \omega \times [0, t]$, whose thickness t > 0 is neglected for simplicity. Here, we consider a uniaxial material with in-plane easy axis \mathbf{e}_1 . With an applied exterior field $\mathbf{f} : \omega \to \mathbb{R}^2$, we seek a minimizer \mathbf{m}^* of the reduced energy

$$e(\mathbf{m}) = \frac{1}{2} \int_{\mathbb{R}^3} |\nabla u|^2 dx + \frac{q}{2} \int_{\omega} \mathbf{m}_2^2 dx - \int_{\omega} \mathbf{f} \cdot \mathbf{m} dx$$
(1)

with the convex side constraint $|\mathbf{m}| \leq 1$. The magnetostatic potential $u : \mathbb{R}^3 \to \mathbb{R}$ is related to the magnetization via

$$\int_{\mathbb{R}^3} \nabla u \cdot \nabla \varphi \, dx = \int_{\omega} \mathbf{m} \cdot \nabla \varphi(x, 0) \, dx \quad \text{for all} \quad \varphi \in \mathscr{D}(\mathbb{R}^3).$$
(2)

In contrast to [2] and [4], where the focus is on a distributional point of view, we give a precise and appropriate functional analytic framework in a certain subspace of $H^{1/2}(\operatorname{div}, \omega) := \{\mathbf{m} \in L^2(\omega)^2 | \nabla \cdot \mathbf{m} \in \widetilde{H}^{-1/2}(\omega)\}$. Existence and uniqueness of a minimizer \mathbf{m}^* in our functional setting is proven. We propose a numerical discretization strategy by use of lowest-order Raviart-Thomas finite elements and provide a priori error estimates. First numerical examples conclude the talk.

- [1] P. BRYANT AND H. SUHL: Thin-film patterns in an external field. *Appl. Phys. Lett.* **54** (1989), 2224–2226.
- [2] A. DESIMONE, R. V. KOHN, S. MÜLLER, AND F. OTTO: A Reduced Theory for Thin-Film Micromagnetics. *Comm. Pure Appl. Math.* Vol. LV (2002), 1408–1460.
- [3] A. DESIMONE, R. V. KOHN, S. MÜLLER, F. OTTO, AND R. SCHÄFER: Two-dimensional modeling of soft ferromagnetic films. Proc. R. Soc. Lond. A 457 (2001), 2983–2991.
- [4] J. DRWENSKI: Numerical methods for a reduced model in thin-flim micromagnetics, Dissertation, University of Bonn, 2008.
- [5] H. A. M. VAN DEN BERG: Self-consistent domain theory in soft-ferromagnetic media. II. Basic domain structures in thin film objects. J. Appl. Phys. **60** (1986), 1104–1113.